

[54] MICROMETER

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Sheffield, England

[**] Term: 14 Years

[21] Appl. No.: 829,988

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[51] Int. Cl. D10—04

[52] U.S. Cl. D10/73

[58] Field of Search D10/70-74,
D10/73; 33/143 M, 143 J, 143 R, 143 K, 143 F

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U.S. PATENT DOCUMENTS

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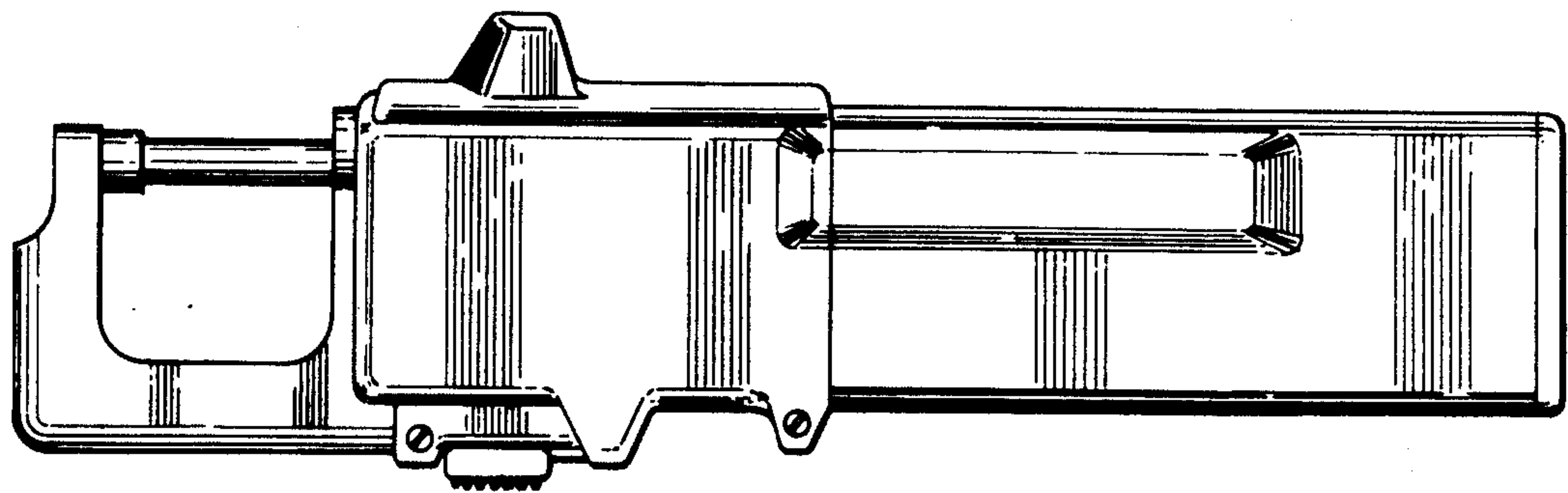
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[57] CLAIM

The ornamental design for a micrometer, substantially as shown.

DESCRIPTION

FIG. 1 is a front elevational view of a micrometer showing my new design;
FIG. 2 is a rear elevational view thereof;
FIG. 3 is a right side elevational view thereof;
FIG. 4 is a left side elevational view thereof;
FIG. 5 is a bottom plan view thereof;
FIG. 6 is a top plan view thereof.



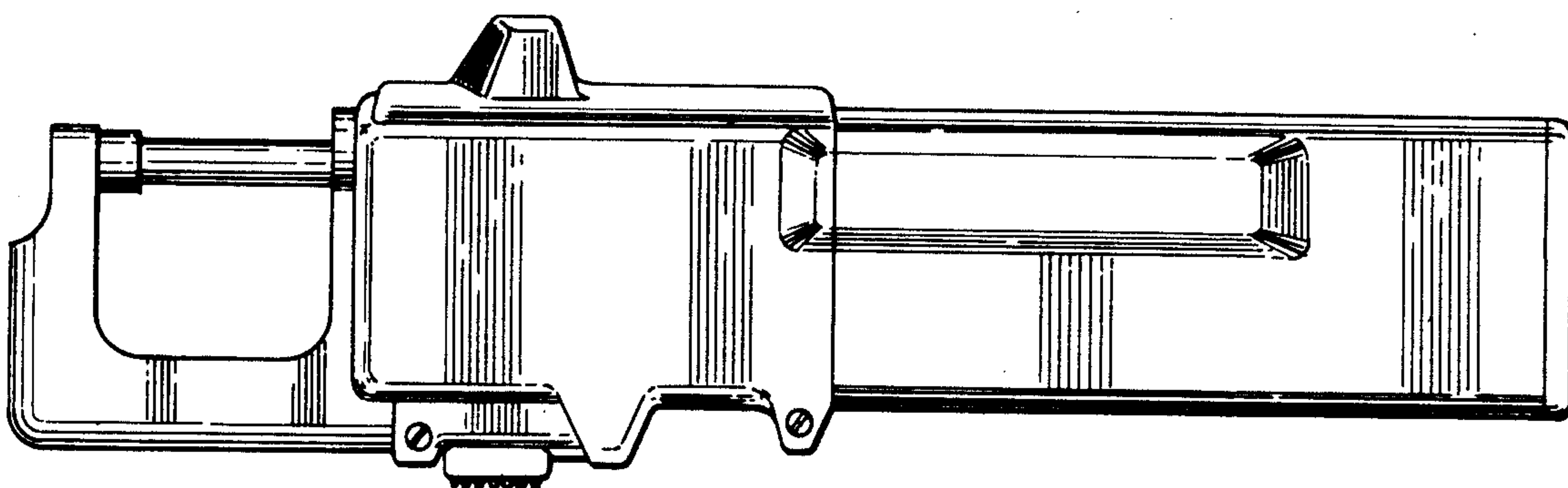


FIG. 1

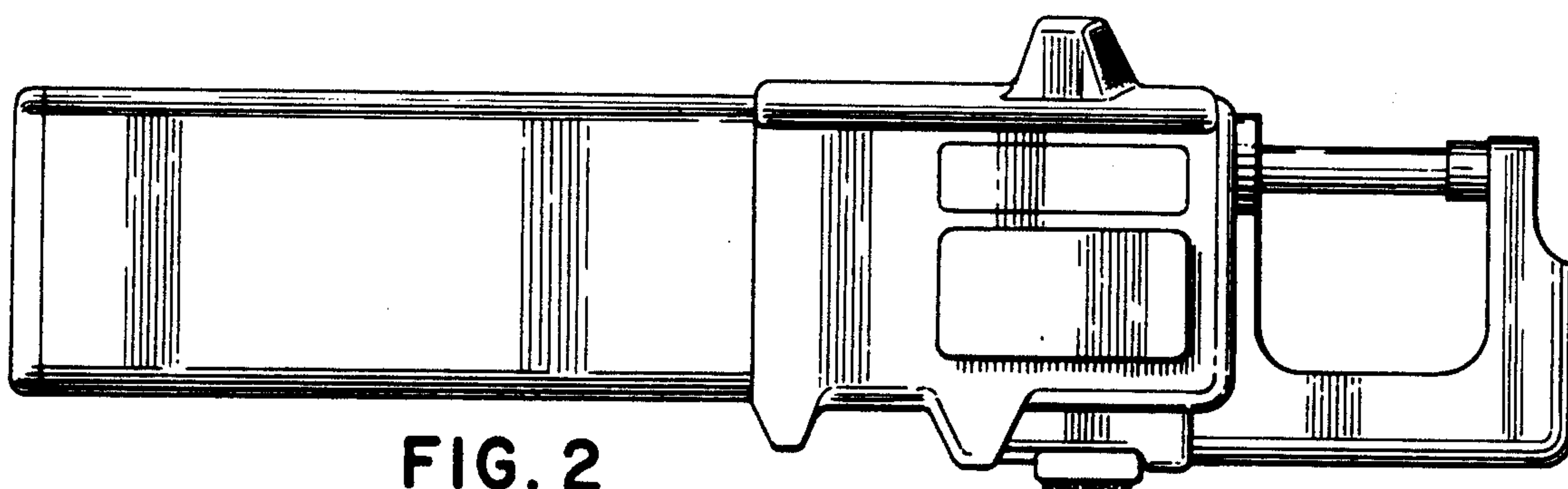


FIG. 2

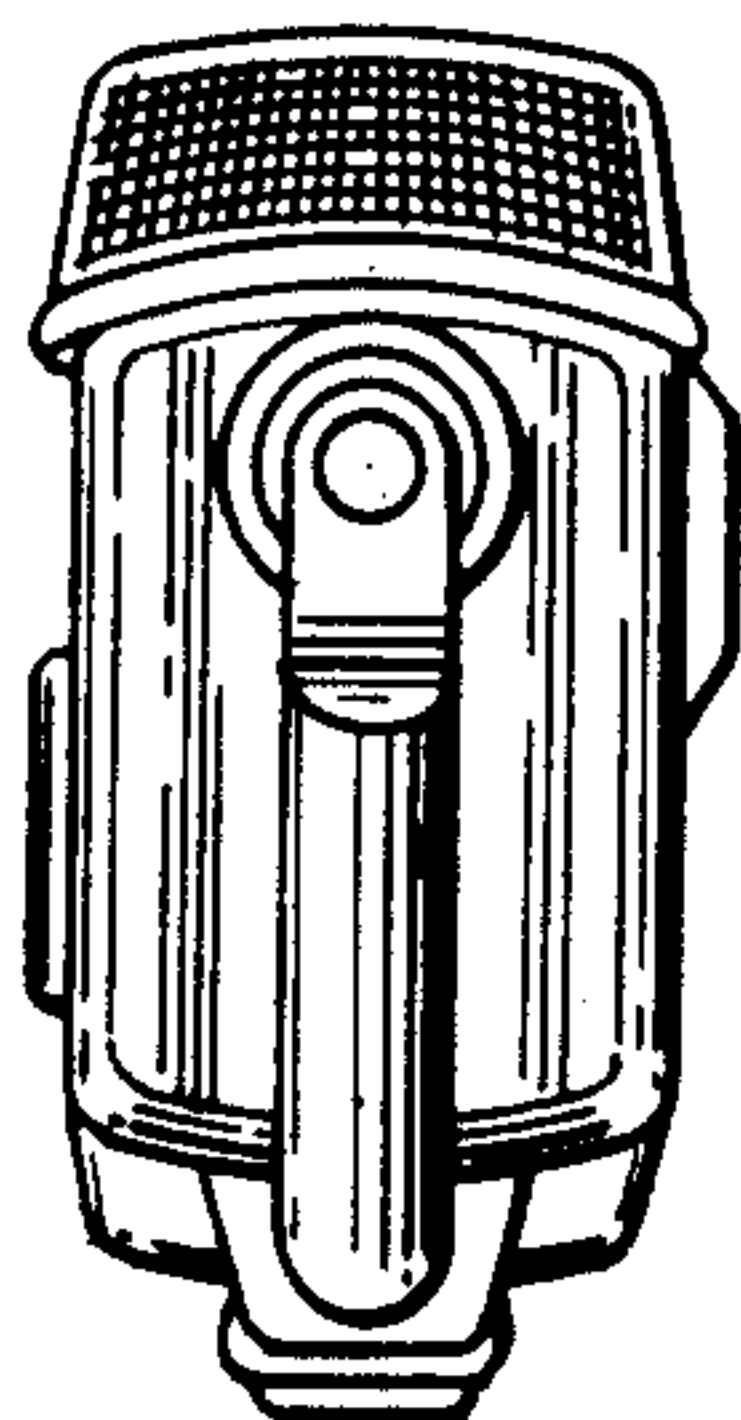


FIG. 3

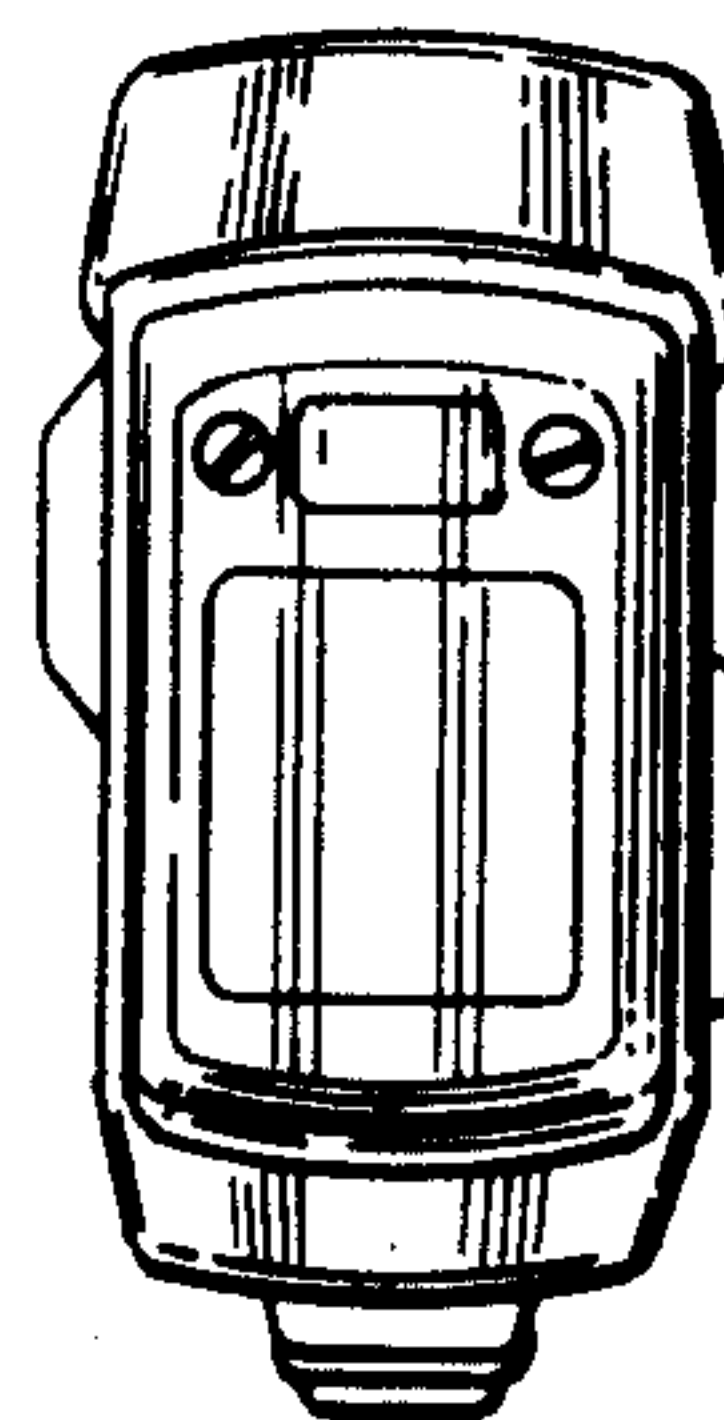


FIG. 4

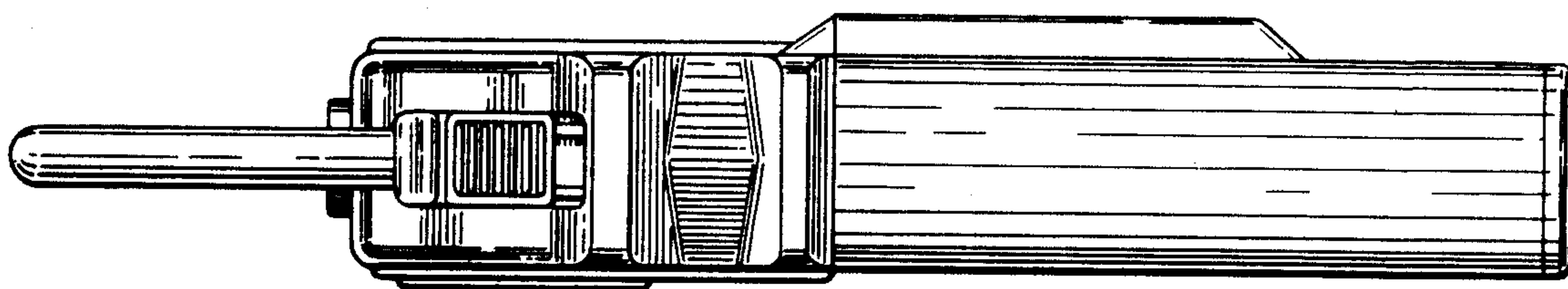


FIG. 5

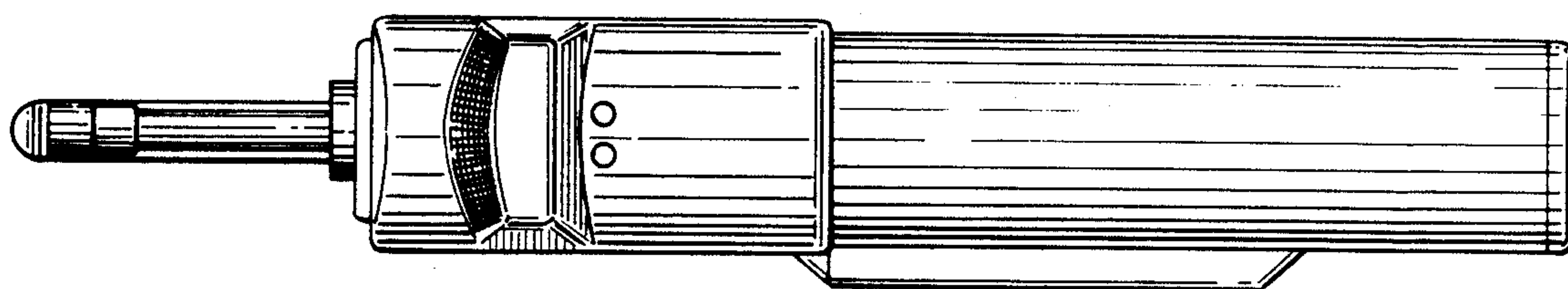


FIG. 6